METHODS AND APPARATUS FOR ANALYZING FLUTTER TEST DATA USING DAMPED SINE CURVE FITTING

ABSTRACT OF THE DISCLOSURE

5   Methods and apparatus for analyzing of flutter test data using damped sine curve fitting are provided. A plurality of data points are read, with each data point representing an amplitude versus a test time. A number "N" of damped sine waves to fit to the plurality of data points is determined, and the number "N" of damped sine waves is fit to the plurality of data points using a non-linear "N" damped sine wave fitting algorithm.

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